

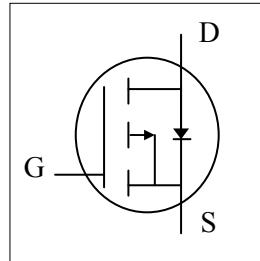


XP4459YT

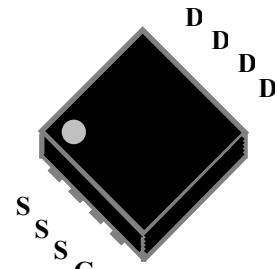
Halogen-Free Product

**P-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

- ▼ Simple Drive Requirement
- ▼ Small Size & Lower Profile
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	-30V
$R_{DS(ON)}$	13.5mΩ
I_D^3	-12.7A



PMPAK® 3x3

Description

XP4459 series are innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The PMPAK® 3x3 package is special for voltage conversion application using standard infrared reflow technique with the backside heat sink to achieve the good thermal performance.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_A = 25^\circ C$	Drain Current, $V_{GS} @ 10V^3$	-12.7	A
$I_D @ T_A = 70^\circ C$	Drain Current, $V_{GS} @ 10V^3$	-10	A
I_{DM}	Pulsed Drain Current ¹	-50	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation ³	3.13	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-c}	Maximum Thermal Resistance, Junction-case	5	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	40	°C/W

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-10\text{A}$	-	-	13.5	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-6\text{A}$	-	-	24	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-10\text{A}$	-	26	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-10	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 0.1	μA
$Q_g(10\text{V})$	Total Gate Charge	$I_{\text{D}}=-10\text{A}$ $V_{\text{DS}}=-15\text{V}$		40	64	nC
$Q_g(4.5\text{V})$	Total Gate Charge		-	20	32	nC
Q_{gs}	Gate-Source Charge		-	7	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	8	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=-15\text{V}$ $I_{\text{D}}=-1\text{A}$	-	12	-	ns
t_r	Rise Time		-	11	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time		-	85	-	ns
t_f	Fall Time		-	47	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$ $V_{\text{DS}}=-15\text{V}$	-	2100	3360	pF
C_{oss}	Output Capacitance		-	300	-	pF
C_{rss}	Reverse Transfer Capacitance		-	250	-	pF
R_g	Gate Resistance	f=1.0MHz	-	10	20	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=-2.6\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=-10\text{A}, V_{\text{GS}}=0\text{V},$ $dI/dt=100\text{A}/\mu\text{s}$	-	16	-	ns
			-	7	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² 2oz copper pad of FR4 board, t \leq 10sec ; 210°C/W when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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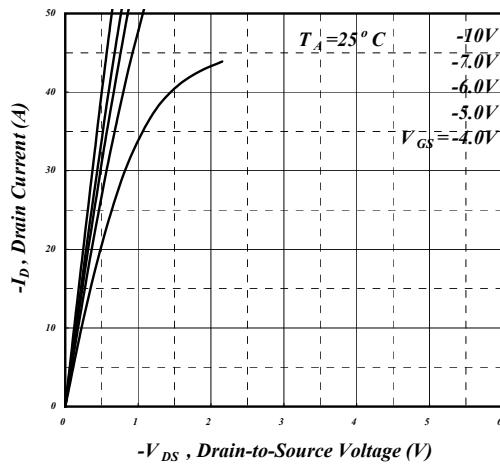


Fig 1. Typical Output Characteristics

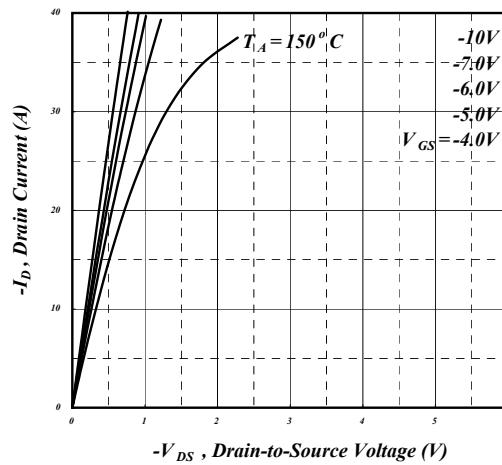


Fig 2. Typical Output Characteristics

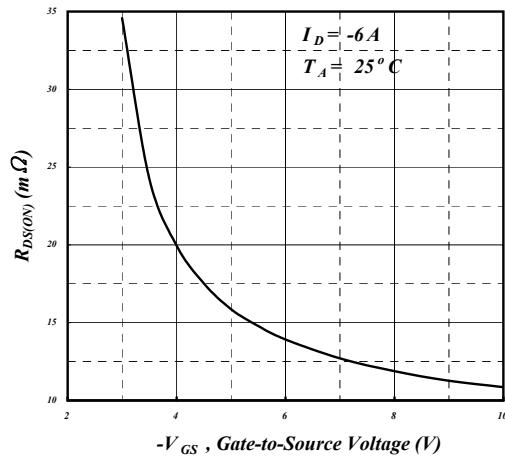


Fig 3. On-Resistance v.s. Gate Voltage

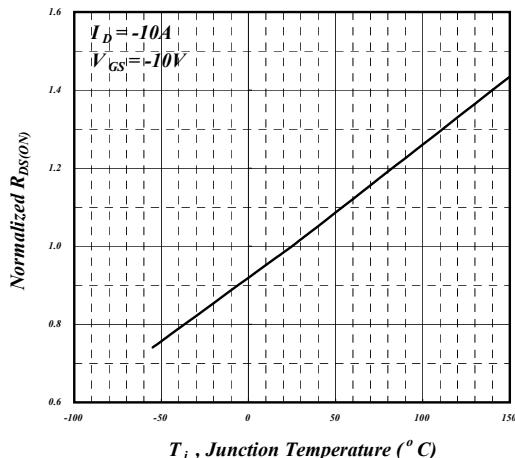


Fig 4. Normalized On-Resistance v.s. Junction Temperature

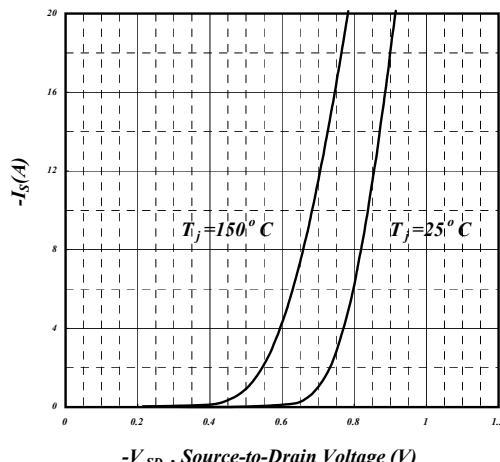


Fig 5. Forward Characteristic of Reverse Diode

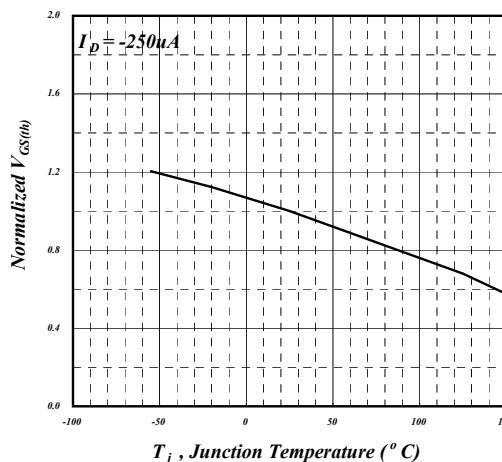


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

